

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under

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KIM, HYON T.

Examiner

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Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0015611	01-2004	Kim, Hyon T.	709/250
	B	US-2003/0217212	11-2003	Kim, Hyon T.	710/305
	C	US-2003/0023705	01-2003	Kim, Hyon T.	709/220
	D	US-2002/0161933	10-2002	Shanthaveeraiah et al.	709/328
	E	US-2002/0161871	10-2002	Shanthaveeraiah et al.	709/223
	F	US-2002/0188711	12-2002	Meyer et al.	709/223
	G	US-6,772,207	08-2004	Dorn et al.	709/224
	H	US-6,769,071	07-2004	Cheng et al.	714/4
	I	US-6,687,766	02-2004	Casper et al.	710/20
	J	US-6,421,711	07-2002	Blumenau et al.	709/213
	K	US-6,311,232	10-2001	Cagle et al.	710/8
	L	US-5,872,932	02-1999	Schettler et al.	709/226
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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